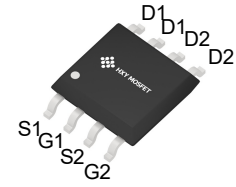




Description

The IRF7319TRPBF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



SOP-8
(SO-8)

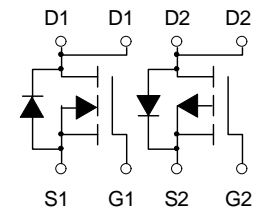
General Features

$V_{DS} = 30V$ $I_D = 6A$

$R_{DS(ON)} < 22m\Omega$ @ $V_{GS}=10V$

$V_{DS} = -30V$ $I_D = -5.5A$

$R_{DS(ON)} < 45 m\Omega$ @ $V_{GS}=-10V$



N-Channel and P-Channel

Application

Wireless charging

Boost driver

Brushless motor

Ordering Information

| Product ID | Pack | Brand | Qty(PCS) |
|--------------|-------------|------------|----------|
| IRF7319TRPBF | SOP-8(SO-8) | HXY MOSFET | 3000 |

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

| Symbol | Parameter | Rating | | Units |
|----------------------|--------------------------------------------------|------------|------------|--------------|
| | | N-Channel | P-Channel | |
| VDS | Drain-Source Voltage | 30 | -30 | V |
| VGS | Gate-Source Voltage | ± 20 | ± 20 | V |
| $I_D@T_A=25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 6 | -5.5 | A |
| $I_D@T_A=70^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 5 | -4.3 | A |
| IDM | Pulsed Drain Current ² | 30 | -30 | A |
| EAS | Single Pulse Avalanche Energy ³ | 5 | 26 | mJ |
| $P_D@T_A=25^\circ C$ | Total Power Dissipation ⁴ | 2 | 2 | W |
| TSTG | Storage Temperature Range | -55 to 150 | -55 to 150 | $^\circ C$ |
| TJ | Operating Junction Temperature Range | -55 to 150 | -55 to 150 | $^\circ C$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | 62.5 | | $^\circ C/W$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 40 | | $^\circ C/W$ |



N-Channel Electrical Characteristics (T_J =25 °C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|-------------------------------------------------------------------------------------------|-----|------|------|-------|
| Static Parameters | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | I _D =250μA, V _{GS} =0V | 30 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =30V, V _{GS} =0V | | | 1 | μA |
| | | T _J =55°C | | | 5 | |
| I _{GSS} | Gate-Body leakage current | V _{DS} =0V, V _{GS} =±20V | | | ±100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _D =250μA | 1.2 | 1.8 | 2.4 | V |
| I _{D(ON)} | On state drain current | V _{GS} =10V, V _{DS} =5V | 30 | | | A |
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} =10V, I _D =6A | | 16 | 22 | mΩ |
| | | T _J =125°C | | 32 | 40 | |
| | | V _{GS} =4.5V, I _D =5A | | 22 | 30 | mΩ |
| g _{FS} | Forward Transconductance | V _{DS} =5V, I _D =6A | | 15 | | S |
| V _{SD} | Diode Forward Voltage | I _S =1A, V _{GS} =0V | | 0.76 | 1 | V |
| I _S | Maximum Body-Diode Continuous Current | | | | 2.5 | A |
| Dynamic Parameters | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =15V, f=1MHz | 200 | 255 | 310 | pF |
| C _{oss} | Output Capacitance | | 30 | 45 | 60 | pF |
| C _{rss} | Reverse Transfer Capacitance | | 20 | 35 | 50 | pF |
| R _g | Gate resistance | V _{GS} =0V, V _{DS} =0V, f=1MHz | 1.6 | 3.25 | 4.9 | Ω |
| Switching Parameters | | | | | | |
| Q _{g(10V)} | Total Gate Charge | V _{GS} =10V, V _{DS} =15V, I _D =6A | 4 | 5.2 | 6 | nC |
| Q _{g(4.5V)} | Total Gate Charge | | 2 | 2.55 | 3 | nC |
| Q _{gs} | Gate Source Charge | | | 0.85 | | nC |
| Q _{gd} | Gate Drain Charge | | | 1.3 | | nC |
| t _{D(on)} | Turn-On DelayTime | V _{GS} =10V, V _{DS} =15V, R _L =2.5Ω, R _{GEN} =3Ω | | 4.5 | | ns |
| t _r | Turn-On Rise Time | | | 2.5 | | ns |
| t _{D(off)} | Turn-Off DelayTime | | | 14.5 | | ns |
| t _f | Turn-Off Fall Time | | | 3.5 | | ns |
| t _{rr} | Body Diode Reverse Recovery Time | I _F =6A, di/dt=100A/μs | | 8.5 | 12 | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | I _F =6A, di/dt=100A/μs | | 2.2 | 3 | nC |

A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C. Ratings are based on low frequency and duty cycles to keep initial T_J=25° C.

D. The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.



Typical Characteristics

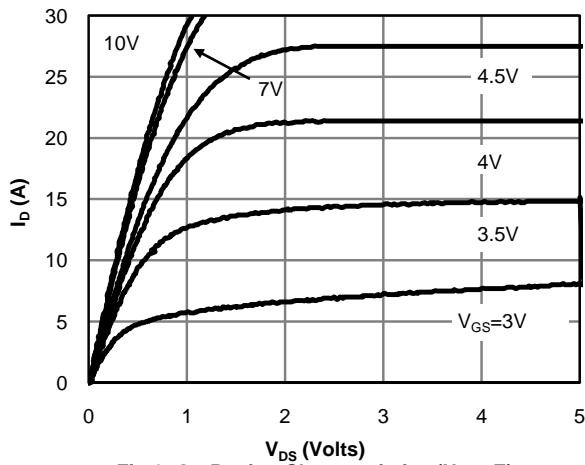


Figure 1: On-Region Characteristics (Note E)

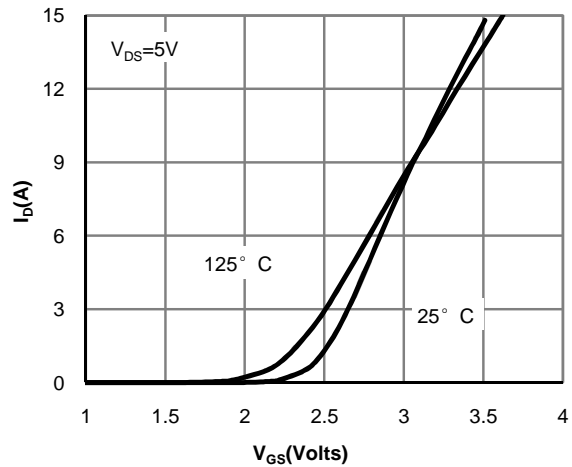


Figure 2: Transfer Characteristics (Note E)

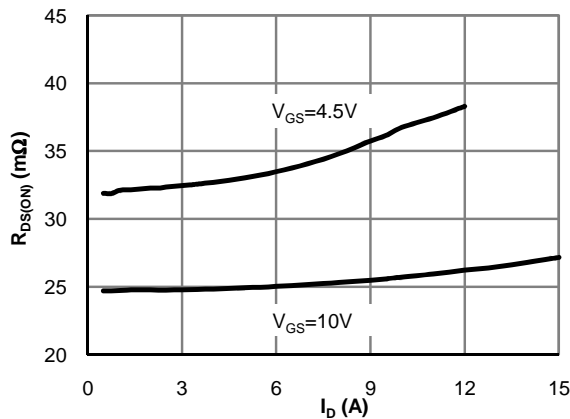


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

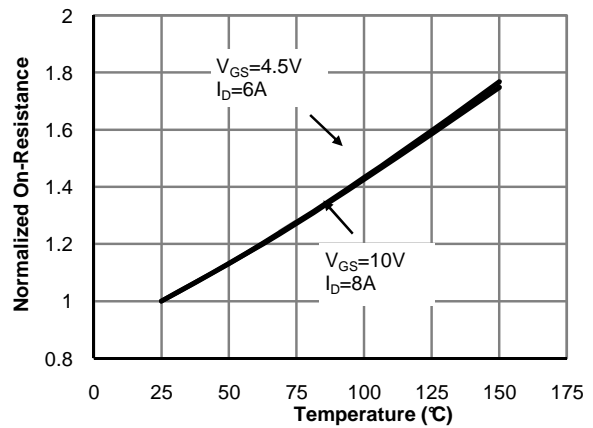


Figure 4: On-Resistance vs. Junction Temperature (Note E)

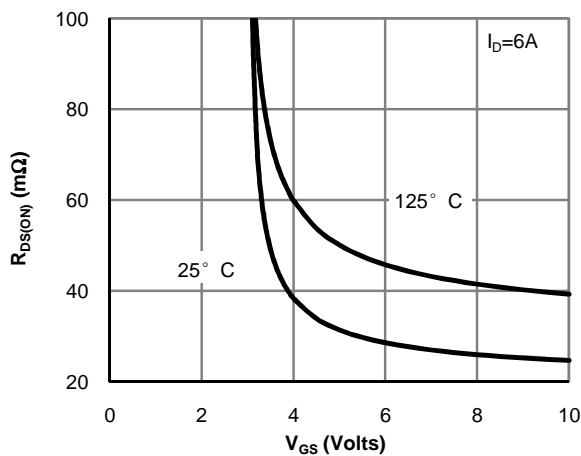


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

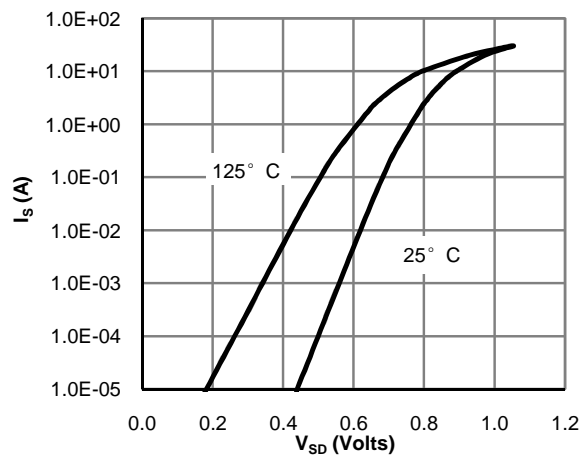


Figure 6: Body-Diode Characteristics (Note E)

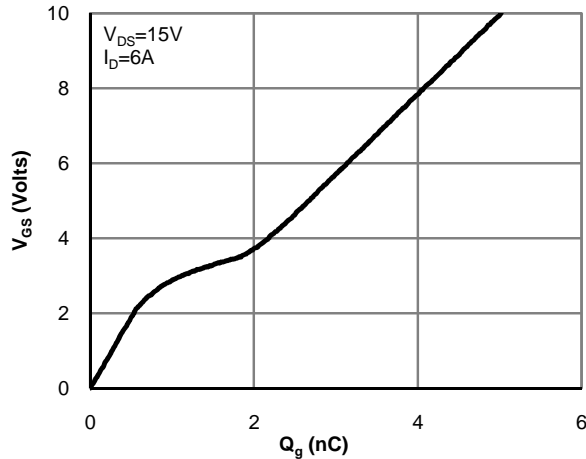


Figure 7: Gate-Charge Characteristics

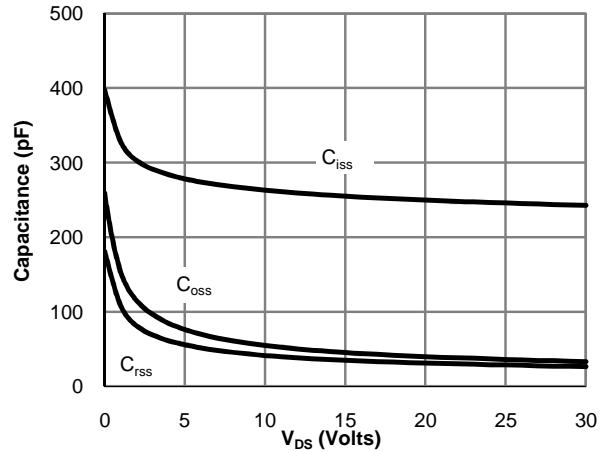


Figure 8: Capacitance Characteristics

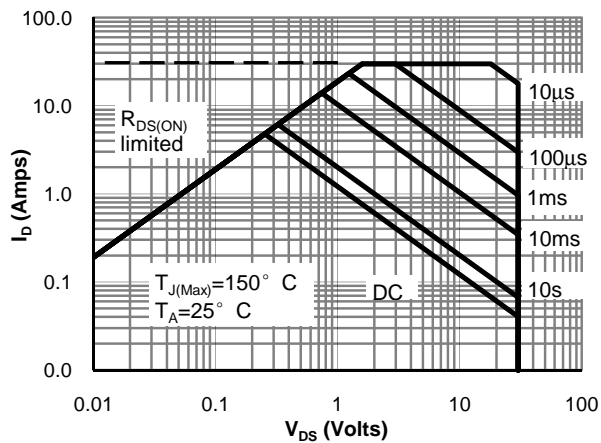


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

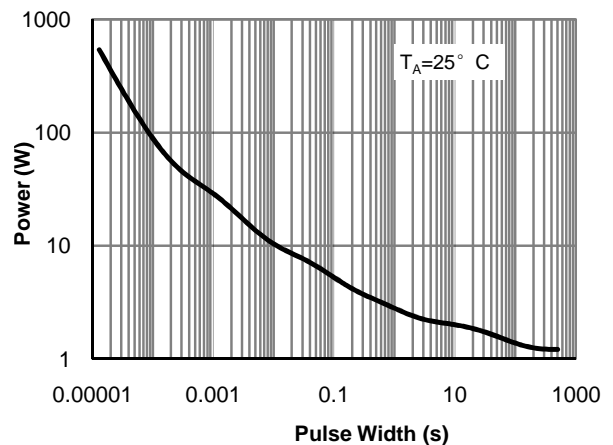


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

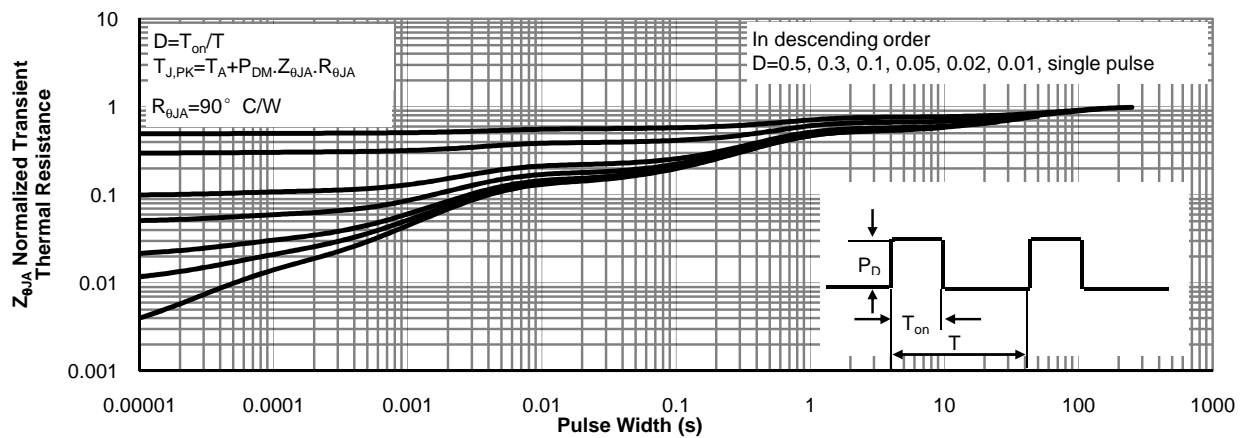
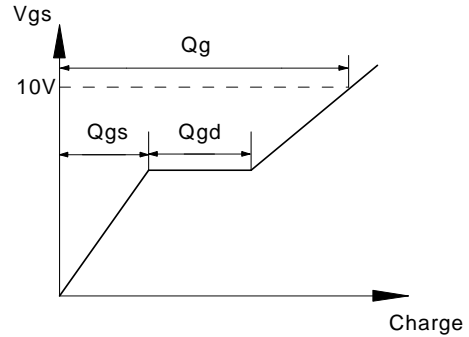
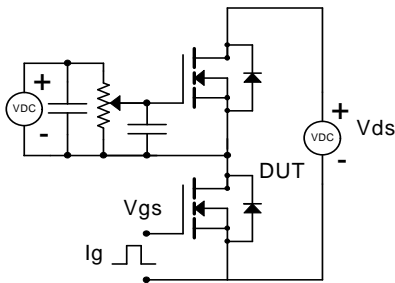


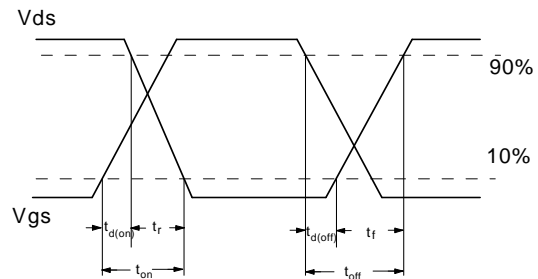
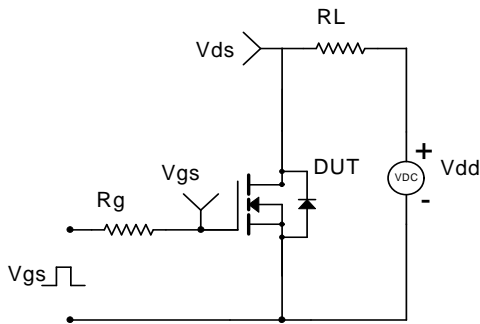
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



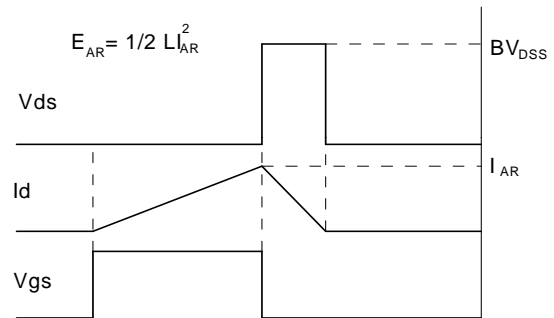
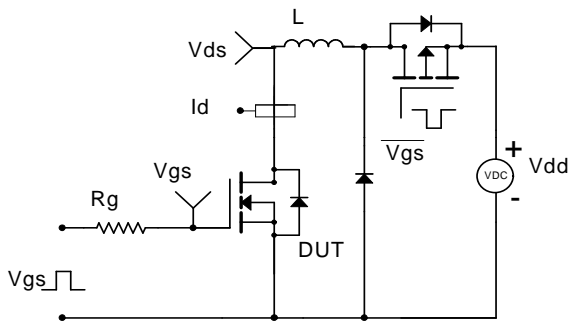
Gate Charge Test Circuit & Waveform



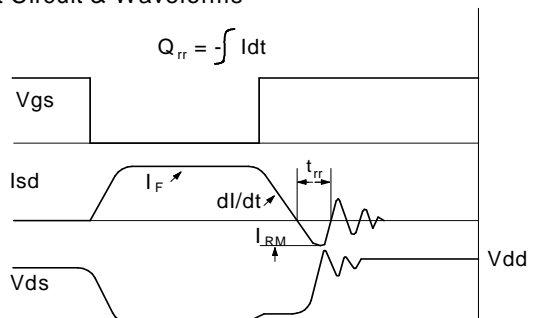
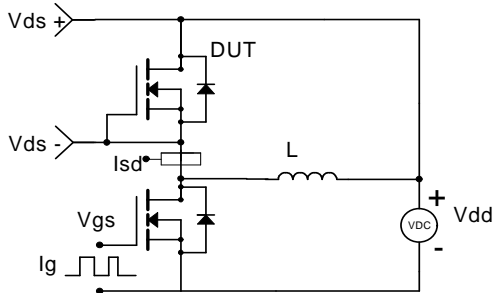
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms





P-Channel Electrical Characteristics (T_J =25 °C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|--------------------------------------------------------------------------------------------|------|----------|----------|-------|
| Static Parameters | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | I _D =-250μA, V _{GS} =0V | -30 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =-30V, V _{GS} =0V T _J =55°C | | | -1 -5 | μA |
| I _{GSS} | Gate-Body leakage current | V _{DS} =0V, V _{GS} =±20V | | | ±100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} I _D =-250μA | -1.3 | -1.85 | -2.4 | V |
| I _{D(ON)} | On state drain current | V _{GS} =-10V, V _{DS} =-5V | -30 | | | A |
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} =-10V, I _D =-6.5A T _J =125°C | | 36 32 | 45 40 | mΩ |
| | | V _{GS} =-4.5V, I _D =-5A | | 68 | 77 | mΩ |
| g _{FS} | Forward Transconductance | V _{DS} =-5V, I _D =-6.5A | | 18 | | S |
| V _{SD} | Diode Forward Voltage | I _S =-1A, V _{GS} =0V | | -0.8 | -1 | V |
| I _S | Maximum Body-Diode Continuous Current | | | | -2.5 | A |
| Dynamic Parameters | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =-15V, f=1MHz | | 760 | | pF |
| C _{oss} | Output Capacitance | | | 140 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 95 | | pF |
| R _g | Gate resistance | V _{GS} =0V, V _{DS} =0V, f=1MHz | 1.5 | 3.2 | 5 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q _g (10V) | Total Gate Charge | V _{GS} =10V, V _{DS} =-15V, I _D =-6.5A | | 13.6 | 16 | nC |
| Q _g (4.5V) | Total Gate Charge | | | 6.7 | 8 | nC |
| Q _{gs} | Gate Source Charge | | | 2.5 | | nC |
| Q _{gd} | Gate Drain Charge | | | 3.2 | | nC |
| t _{D(on)} | Turn-On DelayTime | V _{GS} =10V, V _{DS} =-15V, R _L =2.3Ω, R _{GEN} =3Ω | | 8 | | ns |
| t _r | Turn-On Rise Time | | | 6 | | ns |
| t _{D(off)} | Turn-Off DelayTime | | | 17 | | ns |
| t _f | Turn-Off Fall Time | | | 5 | | ns |
| t _{rr} | Body Diode Reverse Recovery Time | I _F =-6.5A, di/dt=100A/μs | | 15 | | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | I _F =-6.5A, di/dt=100A/μs | | 9.7 | | nC |

A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C. Ratings are based on low frequency and duty cycles to keep initial T_J=25° C.

D. The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.



Typical Characteristics

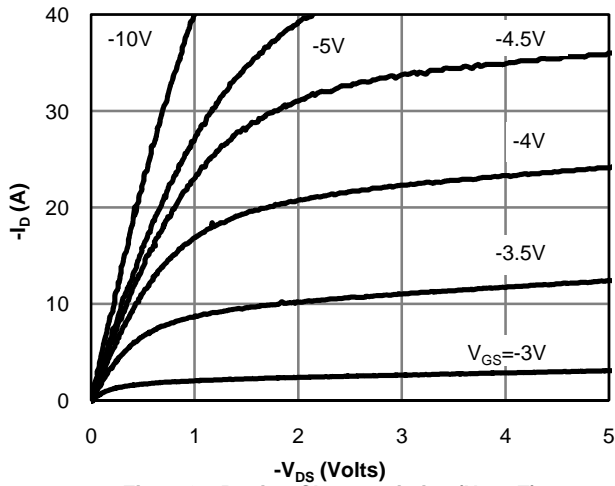


Fig 1: On-Region Characteristics (Note E)

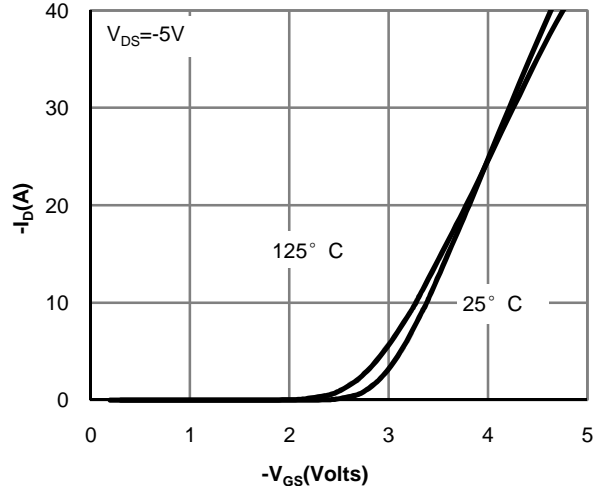


Figure 2: Transfer Characteristics (Note E)

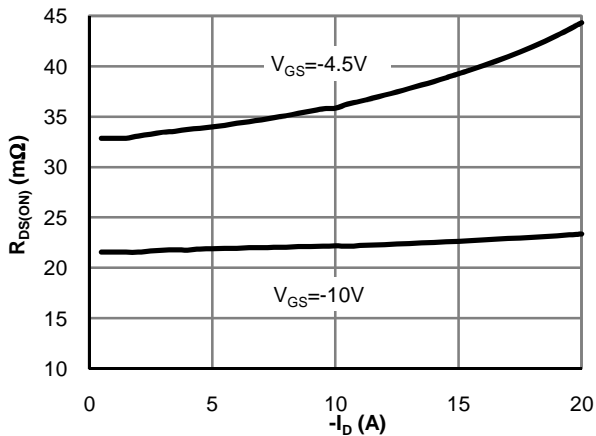


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

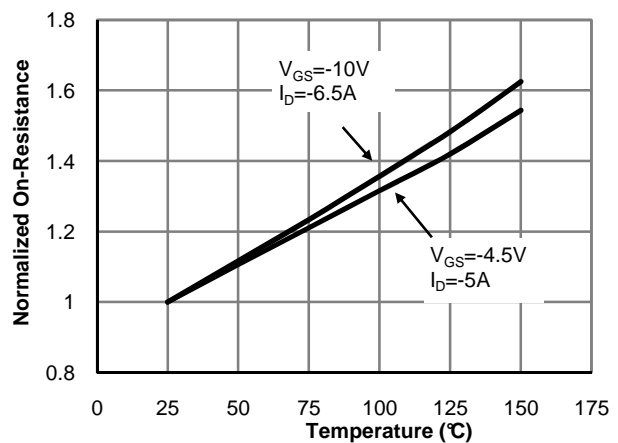


Figure 4: On-Resistance vs. Junction Temperature (Note E)

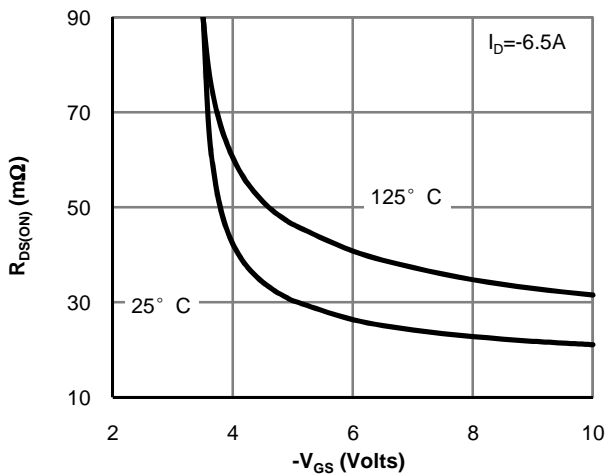


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

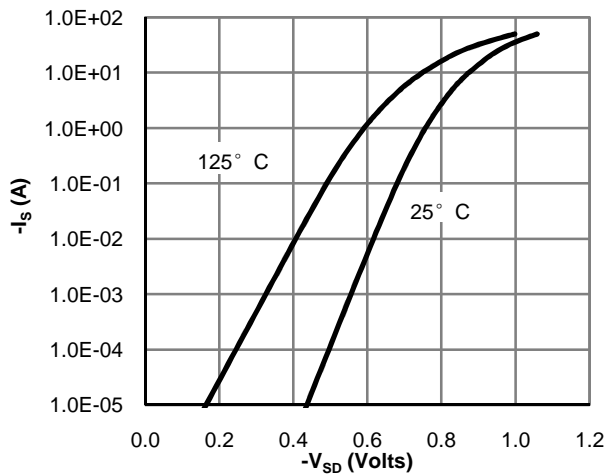


Figure 6: Body-Diode Characteristics (Note E)

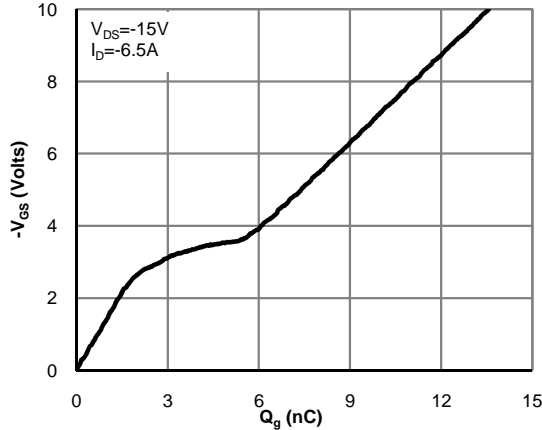


Figure 7: Gate-Charge Characteristics

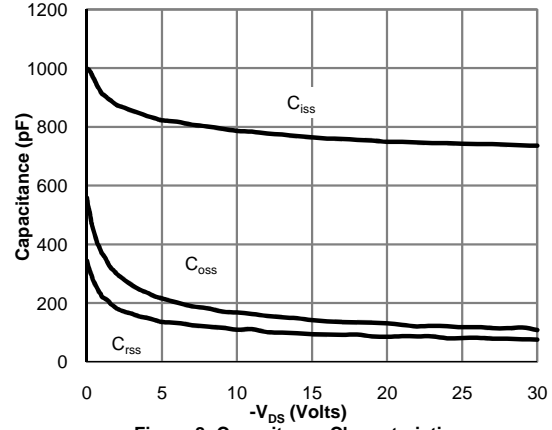


Figure 8: Capacitance Characteristics

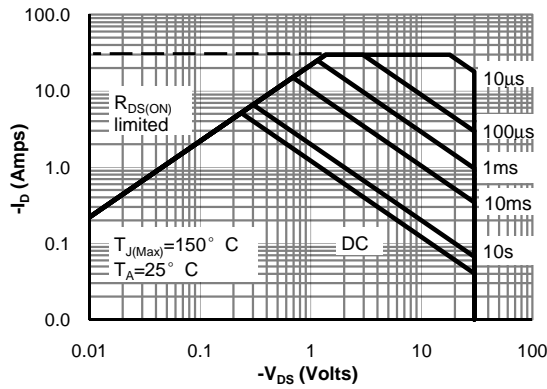


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

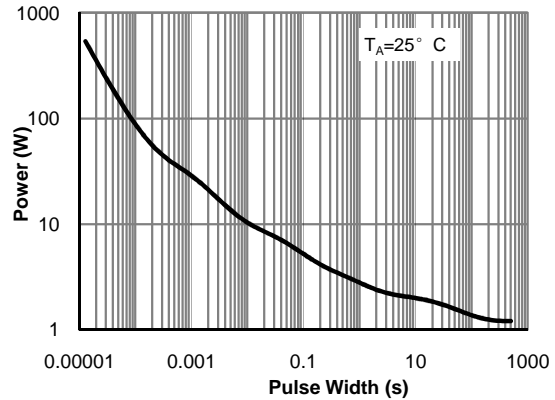


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

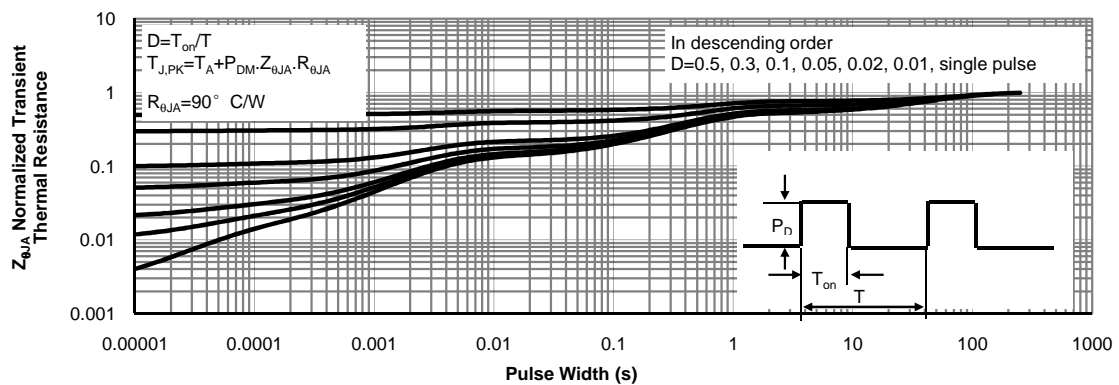
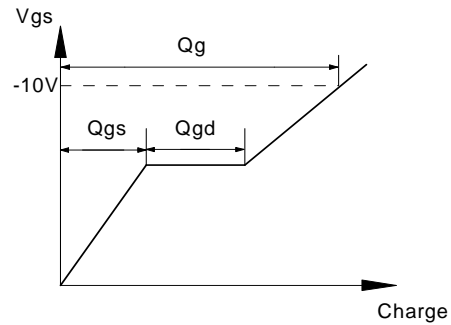
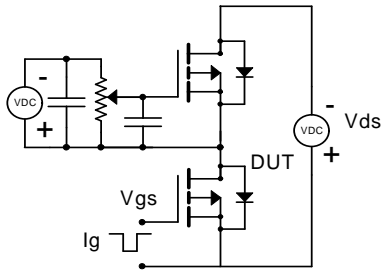


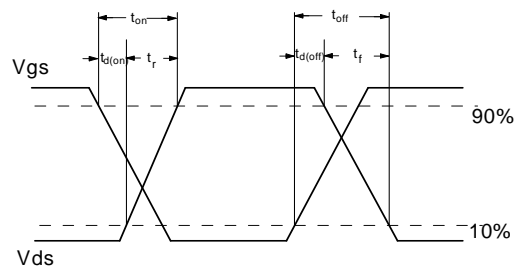
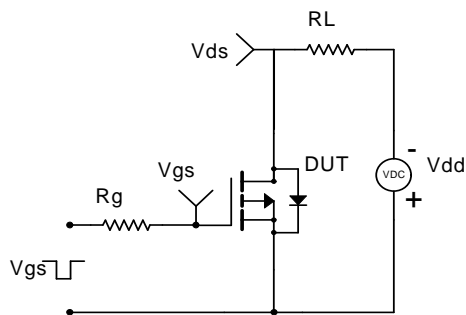
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



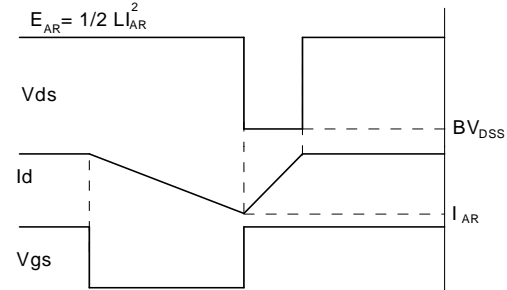
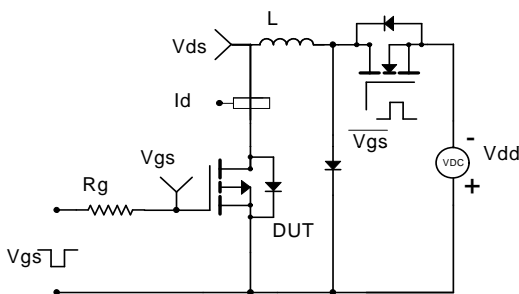
Gate Charge Test Circuit & Waveform



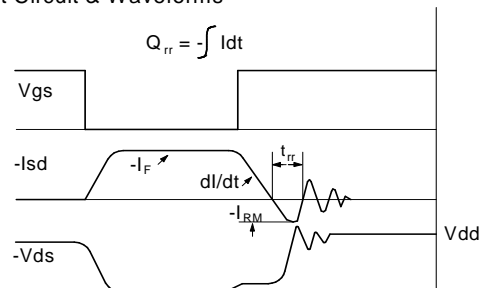
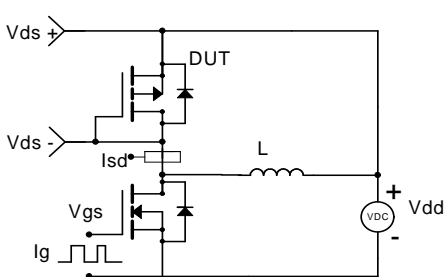
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

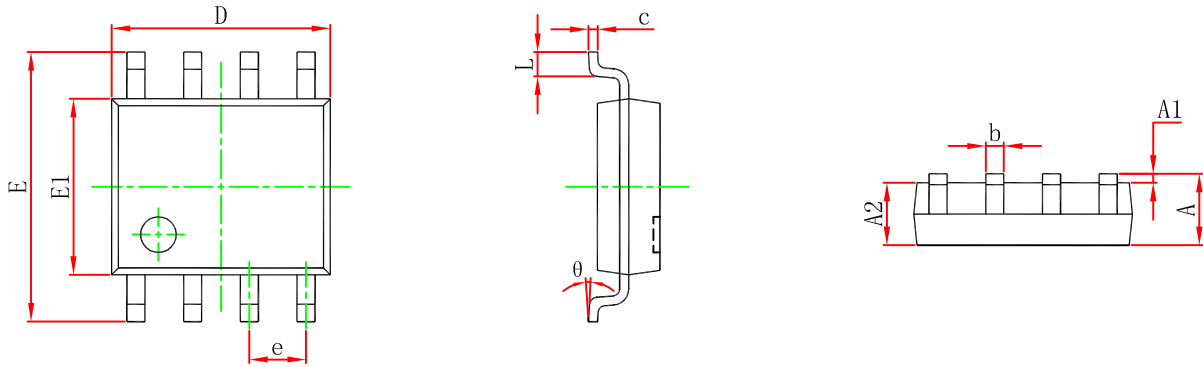


Diode Recovery Test Circuit & Waveforms

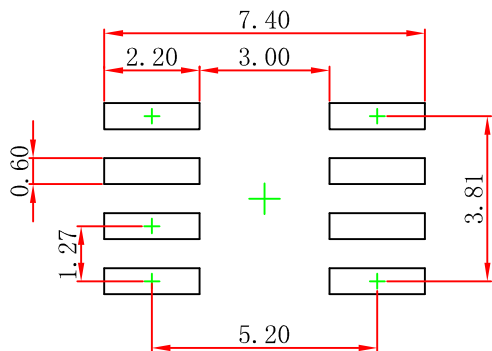




SOP-8(SO-8) Package Outline Dimensions



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min | Max | Min | Max |
| A | 1.350 | 1.750 | 0.053 | 0.069 |
| A1 | 0.100 | 0.250 | 0.004 | 0.010 |
| A2 | 1.350 | 1.550 | 0.053 | 0.061 |
| b | 0.330 | 0.510 | 0.013 | 0.020 |
| c | 0.170 | 0.250 | 0.007 | 0.010 |
| D | 4.800 | 5.000 | 0.189 | 0.197 |
| e | 1.270 (BSC) | | 0.050 (BSC) | |
| E | 5.800 | 6.200 | 0.228 | 0.244 |
| E1 | 3.800 | 4.000 | 0.150 | 0.157 |
| L | 0.400 | 1.270 | 0.016 | 0.050 |
| θ | 0° | 8° | 0° | 8° |



- Note:
1. Controlling dimension: in millimeters.
 2. General tolerance: $\pm 0.05\text{mm}$.
 3. The pad layout is for reference purposes only.



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